

Listing of the Claims

The following listing of claims will replace all prior versions and listings of the claims in the application:

1. (Currently Amended) A method for testing a development device comprising:
 receiving a product specification for the development device, the product specification including an operational description, a plurality of I/O requirements, a plurality of performance parameters, a plurality of physical aspects, wherein the operational description including extracting a plurality of parameters of the development device including one or more parameters for at least one register in the development device from a product specification for the development device, the plurality of parameters being arranged in a predetermined first order includes arranging the one or more parameters for the at least one register in a table, the table including a header, the header including a register name, a register offset and a register type and wherein the table includes a row for each of a plurality of bits in the register and wherein each row includes a bitname and descriptive data field for each bit in the register, wherein the descriptive data field includes a bit type and one or more reset values;
 extracting the plurality of parameters of the development device from the product specification;
 storing the plurality of parameters in a testing data file;
 inputting the testing data file into a test bench system being coupled to the development device; and
 testing the development device.
2. (Canceled)
3. (Currently Amended) The method of ~~claim 2~~ claim 1, wherein receiving the product specification includes converting the product specification from a first format to a second format.
4. (Original) The method of claim 3, wherein the second format is a text format.

5. (Original) The method of claim 1, wherein the plurality of parameters includes any parameters necessary to test a selected operation of the development device.

6. (Canceled)

7. (Canceled)

8. (Canceled)

9. (Canceled)

10. (Original) The method of claim 1, wherein storing the plurality of parameters in a testing data file includes rearranging the plurality of parameters into a second order.

11. (Original) The method of claim 1, wherein the development device is simulated.

12. (Currently Amended) A system for extracting testing data for a development device comprising:

a processor coupled to a computer readable medium having a plurality of computer readable instructions stored thereon including:

logic for receiving a product specification for the development device, the product specification including an operational description, a plurality of I/O requirements, a plurality of performance parameters, a plurality of physical aspects, wherein the operational description including extracting a plurality of parameters of the development device including one or more parameters for at least one register in the development device from a product specification for the development device, the plurality of parameters being arranged in a predetermined first order includes arranging the one or more parameters for the at least one register in a table, the table including a header, the header including a register name, a register offset and a register type and wherein the table includes a row for each of a plurality of bits in the register and wherein each row includes a bitname and descriptive data field for each bit in the register, wherein the descriptive data field includes a bit type and one or more reset values;

logic for extracting the plurality of parameters of the development device from the product specification;

logic for storing the plurality of parameters in a testing data file; and

logic for inputting the testing data file into a test bench system.

13. (Original) The system of claim 12, further comprising a computer network coupled to the processor and wherein the logic for inputting the testing data file into the test bench system includes logic for transmitting the testing data file to the test bench system via the computer network and wherein the test bench system includes logic for testing the development device.

14. (Original) The system of claim 12, further comprising the test bench system and wherein the test bench system includes logic for testing the development device.

15. (Canceled)

16. (Currently Amended) The system of claim 12 ~~claim 15~~, wherein the logic for receiving the product specification includes logic for converting the product specification from a first format to a second format.

17. (Original) The system of claim 12, wherein the plurality of parameters includes any parameters necessary to test a selected operation of the development device.

18. (Canceled)

19. (Original) The system of claim 12, wherein the development device is simulated.

20. (Currently Amended) A test bench system comprising:

a processor;

a storage facility coupled to the processor and containing instructions executable by the processor wherein the instructions include:

logic for receiving a product specification for the development device, the product specification including an operational description, a plurality of I/O requirements, a plurality of performance parameters, a plurality of physical aspects, wherein the operational description including a plurality of parameters of the development device including one or more parameters for at least one register in the development device, the plurality of parameters being arranged

in a predetermined first order includes arranging the one or more parameters for the at least one register in a table, the table including a header, the header including a register name, a register offset and a register type and wherein the table includes a row for each of a plurality of bits in the register and wherein each row includes a bitname and descriptive data field for each bit in the register, wherein the descriptive data field includes a bit type and one or more reset values ~~receiving a product specification, the product specification having a plurality of parameters of the development device, the plurality of parameters being arranged in a predetermined first order;~~

logic for extracting the plurality of parameters from the product specification;

logic for storing the plurality of parameters in a testing data file;

logic for inputting the testing data file into a test bench system; and

logic for testing the development device.